

©1998 Fairchild Semiconductor Corporation

Symbol	Parameter	Conditions	Min	Тур	Max	Units
OFF CHAP	RACTERISTICS					
BV _{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0 V, I_{D} = 250 \mu A$	30			V
$\Delta BV_{DSS}/\Delta T_{J}$	Breakdown Voltage Temp. Coefficient	$I_{\rm D}$ = 250 µA, Referenced to 25 °C		41		mV/ °C
I _{DSS}	Zero Gate Voltage Drain Current	$V_{DS} = 24 \text{ V}, V_{GS} = 0 \text{ V}$ $T_{J} = 55 \text{ °C}$			1	μA
					10	μA
	Gate - Body Leakage, Forward	$V_{GS} = 8 V, V_{DS} = 0 V$			100	nA
I _{GSSR}	Gate - Body Leakage, Reverse	$V_{GS} = -8 V, V_{DS} = 0 V$			-100	nA
	ACTERISTICS (Note)					
V _{GS(th)}	Gate Threshold Voltage	$V_{\rm DS} = V_{\rm GS}, \ I_{\rm D} = 250 \ \mu A$	0.4	0.7	1	V
$\Delta V_{GS(th)} / \Delta T_J$	Gate Threshold Voltage Temp. Coefficient	I_{D} = 250 µA, Referenced to 25 °C		-2.3		mV/ °C
R _{DS(ON)}	Static Drain-Source On-Resistance	$V_{GS} = 4.5 \text{ V}, I_{D} = 2.2 \text{ A}$		0.054	0.065	Ω
		T _J =125℃		0.08	0.11	
		$V_{\rm GS} = 2.5 \text{ V}, \ I_{\rm D} = 2 \text{ A}$		0.07	0.082	
I _{D(ON)}	On-State Drain Current	$V_{GS} = 4.5 \text{ V}, V_{DS} = 5 \text{ V}$	10			Α
9 _{FS}	Forward Transconductance	$V_{DS} = 5 V, I_{D} = 2.2 A$		13		S
DYNAMIC	CHARACTERISTICS					•
C _{iss}	Input Capacitance	$V_{DS} = 10 \text{ V}, V_{GS} = 0 \text{ V},$ f = 1.0 MHz		300		pF
C _{oss}	Output Capacitance			145		pF
C _{rss}	Reverse Transfer Capacitance	7		35		pF
SWITCHIN	G CHARACTERISTICS (Note)					
t _{D(on)}	Turn - On Delay Time	$V_{DD} = 5 V, I_{D} = 1 A,$ $V_{GS} = 4.5 V, R_{GEN} = 6 \Omega$		4	10	ns
ţ	Turn - On Rise Time			10	18	ns
t _{D(off)}	Turn - Off Delay Time			17	28	ns
t,	Turn - Off Fall Time			4	10	ns
Q,	Total Gate Charge	$V_{DS} = 10 \text{ V}, \text{ I}_{D} = 2.2 \text{ A},$ $V_{GS} = 4.5 \text{ V}$		7	9	nC
Q _{gs}	Gate-Source Charge			1.1		nC
Q _{gd}	Gate-Drain Charge			1.9		nC
DRAIN-SO	URCE DIODE CHARACTERISTICS AND M	AXIMUM RATINGS				
l _s	Maximum Continuous Drain-Source Diode Forward Current				0.42	Α
V _{SD}	Drain-Source Diode Forward Voltage $V_{GS} = 0 V, I_{S} = 0.42 A$ (Note)			0.65	1.2	V

1. R_{BA} is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins. R_{BAC} is guaranteed by design while R_{BAC} is determined by the user's board design.

Typical $\rm R_{\rm BM}$ using the board layouts shown below on FR-4 PCB in a still air environment :

а

Scale 1 : 1 on letter size paper

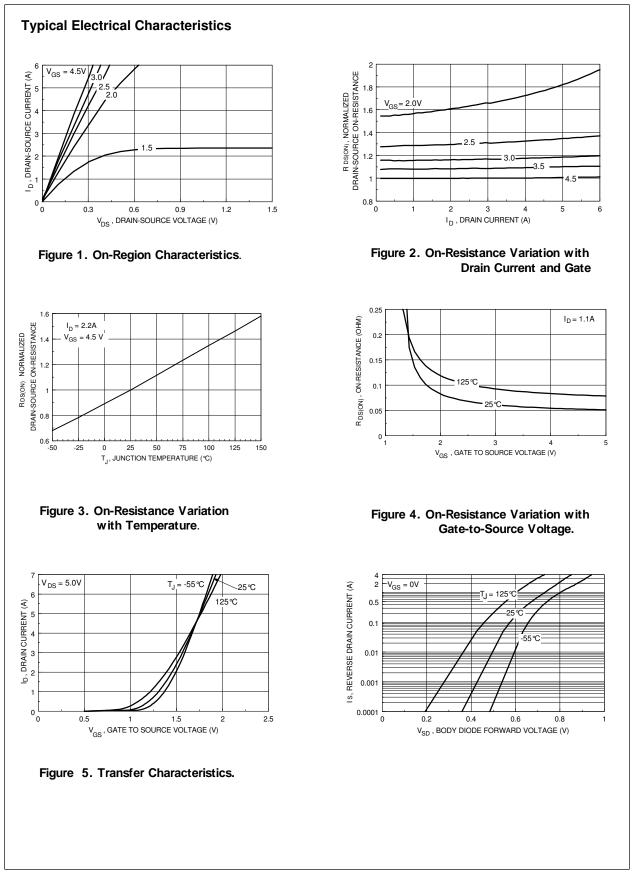
2. Pulse Test: Pulse Width \leq 300µs, Duty Cycle \leq 2.0%.



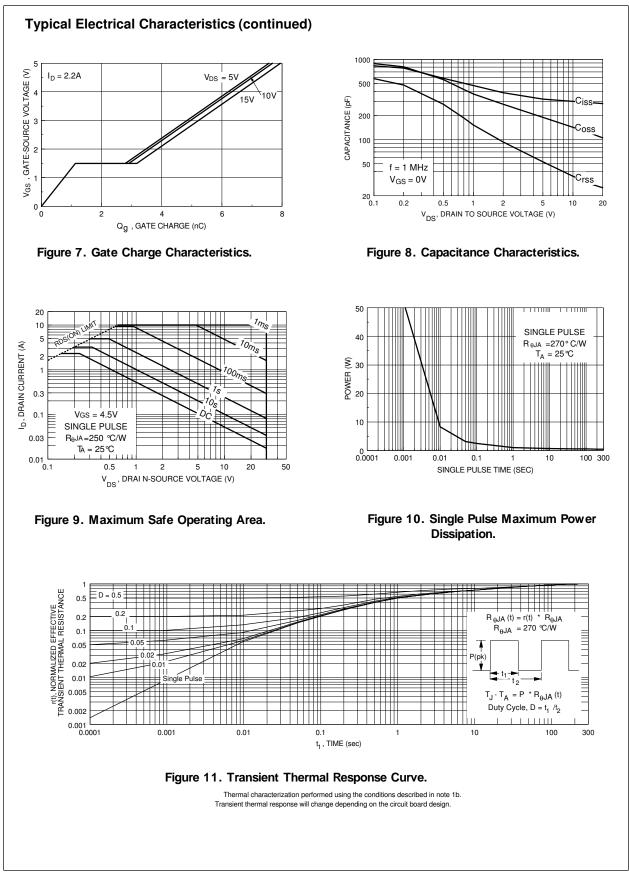
a. 250°C/W when mounted on 0.02 in² pad of 2oz Cu.

1 .\\

b. 270°C/W when mounted on a 0.001 in² pad of 2oz Cu.



FDN337N Rev.C



TRADEMARKS

The following are registered and unregistered trademarks Fairchild Semiconductor owns or is authorized to use and is not intended to be an exhaustive list of all such trademarks.

ACEx™ Bottomless™ CoolFET™ *CROSSVOLT*™ DenseTrench™ DOME™ **EcoSPARK™** E²CMOS[™] EnSigna™ FACT™ FACT Quiet Series[™] FAST ® FASTr™ FRFET™ GlobalOptoisolator[™] POP[™] GTO™ HiSeC™ ISOPLANAR™ LittleFET™ MicroFET™ MicroPak™ MICROWIRE™

OPTOLOGIC™ OPTOPLANAR™ PACMAN™ Power247[™] PowerTrench[®] QFET™ OS™ QT Optoelectronics[™] Quiet Series[™] SILENT SWITCHER®

SMART START™ VCX™ STAR*POWER™ Stealth™ SuperSOT™-3 SuperSOT[™]-6 SuperSOT[™]-8 SyncFET™ TinyLogic™ TruTranslation™ UHC™ UltraFET[®]

STAR*POWER is used under license

DISCLAIMER

FAIRCHILD SEMICONDUCTOR RESERVES THE RIGHT TO MAKE CHANGES WITHOUT FURTHER NOTICE TO ANY PRODUCTS HEREIN TO IMPROVE RELIABILITY. FUNCTION OR DESIGN. FAIRCHILD DOES NOT ASSUME ANY LIABILITY ARISING OUT OF THE APPLICATION OR USE OF ANY PRODUCT OR CIRCUIT DESCRIBED HEREIN; NEITHER DOES IT CONVEY ANY LICENSE UNDER ITS PATENT RIGHTS. NOR THE RIGHTS OF OTHERS.

LIFE SUPPORT POLICY

FAIRCHILD'S PRODUCTS ARE NOT AUTHORIZED FOR USE AS CRITICAL COMPONENTS IN LIFE SUPPORT DEVICES OR SYSTEMS WITHOUT THE EXPRESS WRITTEN APPROVAL OF FAIRCHILD SEMICONDUCTOR CORPORATION. As used herein:

1. Life support devices or systems are devices or systems which, (a) are intended for surgical implant into the body, or (b) support or sustain life, or (c) whose failure to perform when properly used in accordance with instructions for use provided in the labeling, can be reasonably expected to result in significant injury to the user.

2. A critical component is any component of a life support device or system whose failure to perform can be reasonably expected to cause the failure of the life support device or system, or to affect its safety or effectiveness.

PRODUCT STATUS DEFINITIONS

Definition of Terms

Product Status	Definition	
Formative or In Design	This datasheet contains the design specifications for product development. Specifications may change in any manner without notice.	
First Production	This datasheet contains preliminary data, and supplementary data will be published at a later date. Fairchild Semiconductor reserves the right to make changes at any time without notice in order to improve design.	
Full Production	This datasheet contains final specifications. Fairchild Semiconductor reserves the right to make changes at any time without notice in order to improve design.	
Not In Production	This datasheet contains specifications on a product that has been discontinued by Fairchild semiconducto The datasheet is printed for reference information on	
	Formative or In Design First Production Full Production	

Rev. H4